

Notice of References Cited	Application/Control No. 10/721,673		Applicant(s)/Patent Under Reexamination QIN ET AL.	
	Examiner Phallaka Kik		Art Unit 2825	Page 1 of 3

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	Examiner Phallaka Kik		Art Unit 2825	Page 2 of 3

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	Examiner Phallaka Kik		Art Unit 2825	Page 3 of 3

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